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Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









AS7C316098A 1024K X 16 BIT HIGH SPEED CMOS SRAM

REVISION HISTORY

<u>Revision</u>	Description	Issue Date
Rev. 1.0	Initial Issued	Jan.09. 2012
Rev. 1.1	Add 48 pin BGA package type.	Mar.12. 2012
Rev. 1.2	1."CE# ≥ V _{CC} - 0.2V" revised as "CE# ≤ 0.2" for TEST CONDITION of Average Operating Power supply Current lcc1 on page3	July.19. 2012
	2 Revised ORDERING INFORMATION Page 11	



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FEATURES

Fast access time: 10nslow power consumption:

Operating current: 90mA (typical) Standby current: 4mA(Typical)

- Single 3.3V power supply
- All inputs and outputs TTL compatible
- Fully static operation
- · Tri-state output
- Data byte control : LB# (DQ0 ~ DQ7)
 UB# (DQ8 ~ DQ15)
- Data retention voltage: 1.5V (MIN.)
- Green package available
- Package: 48-pin 12mm x 20mm TSOP-I 48-ball 6mmx8mm TFBGA

GENERAL DESCRIPTION

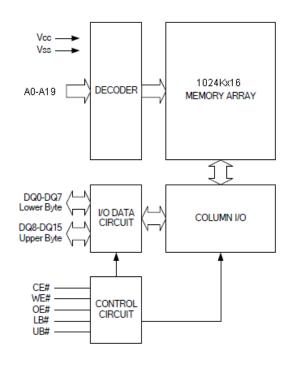
The AS7C316098A is a 16M-bit high speed CMOS static random access memory organized as 1024K words by 16 bits. It is fabricated using very high performance, high reliability CMOS technology. Its standby current is stable within the range of operating temperature.

The AS7C316098A operates from a single power supply of 3.3V and all inputs and outputs are fully TTL compatible

PRODUCT FAMILY

Product	Operating	Vcc Range	Spood	Power [Dissipation
Family	Temperature	vcc hange	Speed	Standby(IsB1,TYP.)	Operating(Icc1,TYP.)
AS7C316098A(I)	-40 ~ 85℃	2.7 ~ 3.6V	10ns	4mA	90mA

FUNCTIONAL BLOCK DIAGRAM



PIN DESCRIPTION

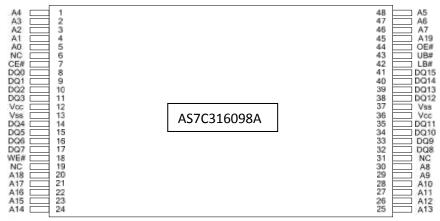
SYMBOL	DESCRIPTION
A0 - A19	Address Inputs
DQ0 – DQ15	Data Inputs/Outputs
CE#	Chip Enable Input
WE#	Write Enable Input
OE#	Output Enable Input
LB#	Lower Byte Control
UB#	Upper Byte Control
Vcc	Power Supply
Vss	Ground



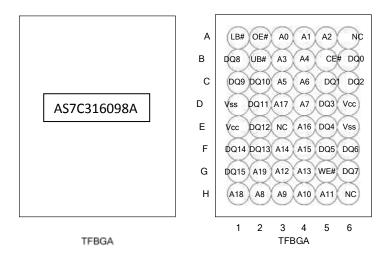
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PIN CONFIGURATION



TSOP-I



ABSOLUTE MAXIMUN RATINGS*

PARAMETER	SYMBOL	RATING	UNIT
Voltage on Vcc relative to Vss	V _{T1}	-0.5 to 4.6	V
Voltage on any other pin relative to Vss	V T2	-0.5 to Vcc+0.5	V
Operating Temperature	TA	0 to 70(C grade)	${\mathbb C}$
Operating Temperature	TA	-40 to 85(I grade)	
Storage Temperature	Тѕтс	-65 to 150	${\mathbb C}$
Power Dissipation	PD	1	W
DC Output Current	Іоит	50	mA

^{*}Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to the absolute maximum rating conditions for extended period may affect device reliability.



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TRUTH TABLE

MODE	CE#	OE#	WE#	LB#	UB#	I/O OPERATION		SUPPLY CURRENT
IIIODE	O_"	OL,	***	LDII	OD#	DQ0-DQ7	DQ8-DQ15	OOT I ET OOTHIENT
Standby	Н	X	Х	Χ	Х	High – Z	High – Z	lsb , I _{SB1,}
Output Disable	L	Н	H	X	X	High – Z	High – Z	lcc
Output Bloadio	L	Х	X	Ι	Н	High – Z	High – Z	.00
	L	L	Н	L	Н	D_OUT	High – Z	
Read	L	L	Н	Н	L	High – Z	D_OUT	Icc
	L	L	Н	L	L	D_OUT	D_OUT	
	L	Χ	L	L	Н	D_IN	High – Z	
Write	L	Χ	L	Н	L	High – Z	D_IN	Icc
	L	Χ	L	L	L	D_IN	D_IN	

Note: $H = V_{IH}$, $L = V_{IL}$, X = Don't care.

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	TEST CONDITION		TYP. ^{^4}	MAX.	UNIT
Supply Voltage	Vcc			2.7	3.3	3.6	V
Input High Voltage	V _{IH} ^{*1}			2.2	-	Vcc+0.3	V
Input Low Voltage	V _{IL} *2			- 0.3	-	0.8	V
Input Leakage Current	lu	$V_{CC} \ge V_{IN} \ge V_{SS}$		- 1	-	1	μΑ
Output Leakage Current	ILO	$V_{CC} \ge V_{OUT} \ge V_{SS},$ Output Disabled		- 1	-	1	μΑ
Output High Voltage	V _{OH}	I _{OH} = -8mA		2.4	-	-	V
Output Low Voltage	V _{OL}	I _{OL} =4mA		-	-	0.4	٧
AverageOperating	lcc	CE# = V _{IL} , I _{VO} = 0mA ;f=max	-10	-	110	160	mA
Power supply Current	lcc1	CE# \leq 0.2, Other pin is at 0.2V or Vcc-0.2V $I_{I/O} = 0$ mA; $f = max$	-10	-	90	120	mA
Standby Power Supply Current	Isb	CE# ≧ Vih Other pin is at Vil or Vih		-	-	80	mA
Standby Power Supply Current	I _{SB1}	CE# \geq Vcc - 0.2V; Other pin is at 0.2V or Vcc-	0.2V	-	4	40	mA

Notes:

- 1. VIH(max) = VCC + 3.0V for pulse width less than 10ns.

Vil(midx) = Vos + o.ov for pulse width less than 10ns.
 Vil(min) = Vss - 3.0V for pulse width less than 10ns.
 Over/Undershoot specifications are characterized, not 100% tested.
 Typical values are included for reference only and are not guaranteed or tested.
 Typical valued are measured at Vcc = Vcc(TYP.) and TA = 25 °C



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CAPACITANCE (TA = 25°C, f = 1.0MHz)

PARAMETER	SYMBOL	MIN.	MAX	UNIT
Input Capacitance	Cin	-	8	pF
Input/Output Capacitance	CI/O	-	10	pF

Note: These parameters are guaranteed by device characterization, but not production tested.

AC TEST CONDITIONS

speed	10/12ns
Input Pulse Levels	0.2V to Vcc-0.2V
Input Rise and Fall Times	3ns
Input and Output Timing Reference Levels	Vcc/2
Output Load	$C_L = 30pF + 1TTL$,
Output Load	IOH/IOL = -8mA/4mA

AC ELECTRICAL CHARACTERISTICS

(1) READ CYCLE

(1) READ CICEE	0)/14	AS7C3160	98A-10	
PARAMETER	SYM.	MIN.	MAX.	UNIT
Read Cycle Time	trc	10	-	ns
Address Access Time	taa	-	10	ns
Chip Enable Access Time	tace	-	10	ns
Output Enable Access Time	toe	-	4.5	ns
Chip Enable to Output in Low-Z	tcLz*	2	-	ns
Output Enable to Output in Low-Z	tolz*	0	-	ns
Chip Disable to Output in High-Z	tcHz*	-	4	ns
Output Disable to Output in High-Z	toнz*	-	4	ns
Output Hold from Address Change	tон	2	-	ns
LB#, UB# Access Time	tва	-	4.5	ns
LB#, UB# to High-Z Output	tвнz*	-	4	ns
LB#, UB# to Low-Z Output	tBLZ*	0	-	ns

(2) WRITE CYCLE

PARAMETER	SYM.	AS7C3160	98A-10	UNIT
PARAMETER	STIVI.	MIN.	MAX.	UNII
Write Cycle Time	twc	10	-	ns
Address Valid to End of Write	taw	8	-	ns
Chip Enable to End of Write	tcw	8	-	ns
Address Set-up Time	tas	0	-	ns
Write Pulse Width	twp	8	-	ns
Write Recovery Time	twr	0	-	ns
Data to Write Time Overlap	tow	6	-	ns
Data Hold from End of Write Time	tдн	0	-	ns
Output Active from End of Write	tow*	2	-	ns
Write to Output in High-Z	tw _{HZ} *	-	4	ns
LB#, UB# Valid to End of Write	tвw	8	-	ns

^{*}These parameters are guaranteed by device characterization, but not production tested.

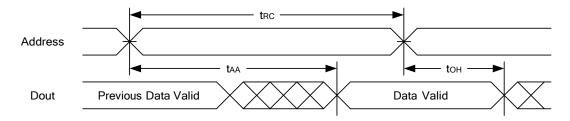
Alliance Memory, Inc.



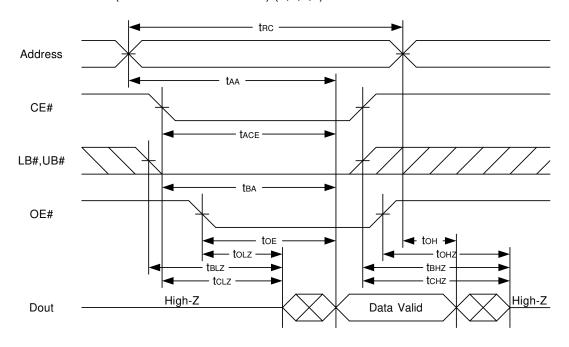
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TIMING WAVEFORMS

READ CYCLE 1 (Address Controlled) (1,2)



READ CYCLE 2 (CE# and OE# Controlled) (1,3,4,5)



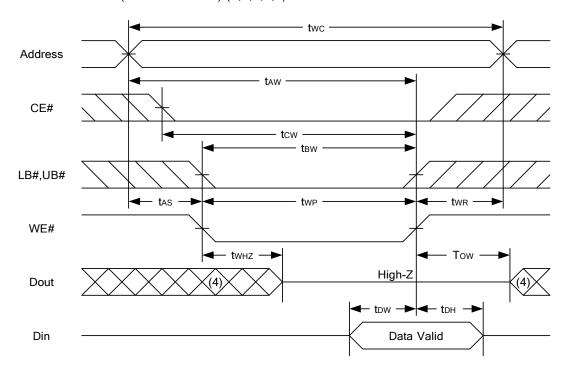
Notes:

- 1.WE#is high for read cycle.
- 2.Device is continuously selected OE# = low, CE# = low, LB# or UB# = low.
- 3.Address must be valid prior to or coincident with CE# = low, LB# or UB# = low transition; otherwise tAA is the limiting parameter.
- 4.tclz, tBLz, tolz, tcHz, tBHz and toHz are specified with CL = 5pF. Transition is measured $\pm 500mV$ from steady state.
- 5.At any given temperature and voltage condition, t_{CHZ} is less than t_{CLZ}, t_{BHZ} is less than t_{BLZ}, t_{OHZ} is less than t_{CLZ}

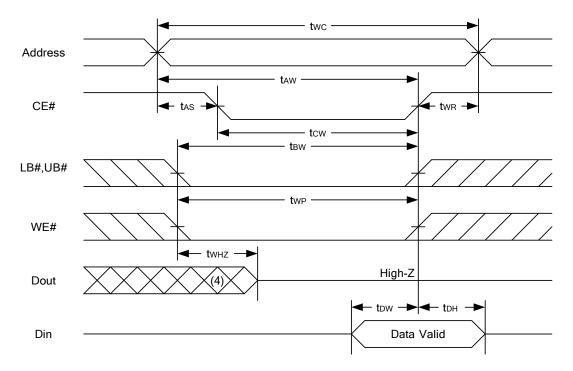


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WRITE CYCLE 1 (WE# Controlled) (1,2,3,5,6)



WRITE CYCLE 2 (CE# Controlled) (1,2,5,6)

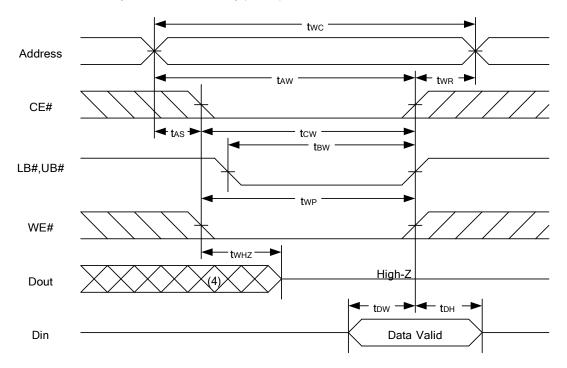




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WRITE CYCLE 3 (LB#,UB# Controlled) (1,2,5,6)



- 1.WE#,CE#, LB#, UB# must be high during all address transitions.
 2.A write occurs during the overlap of a low CE#, low WE#, LB# or UB# = low.
- 3. During a WE# controlled write cycle with OE# low, twp must be greater than twHz + tow to allow the drivers to turn off and data to be placed on the bus.
- 4. During this period, I/O pins are in the output state, and input signals must not be applied.
- 5.If the CE#, LB#, UB# low transition occurs simultaneously with or after WE# low transition, the outputs remain in a high impedance state.
- 6.tow and twHz are specified with $C_L = 5pF$. Transition is measured ± 500 mV from steady state.



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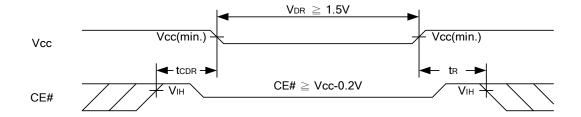
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DATA RETENTION CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Vcc for Data Retention		$CE\# \geq V_{CC} - 0.2V$	1.5	-	3.6	V
Data Retention Current	IDR	V_{CC} = 1.5 V $CE\# \ge V_{CC}$ - 0.2 V ; Other pin is at 0.2 V or V_{CC} -0.2 V	-	4	40	mA
Chip Disable to Data Retention Time	I ICDD	See Data Retention Waveforms (below)	0	-	-	ns
Recovery Time	tr		trc∗	-	-	ns

tRC* = Read Cycle Time

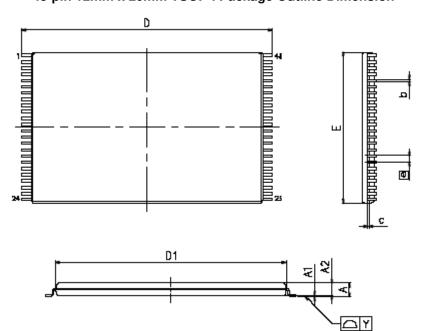
DATA RETENTION WAVEFORM

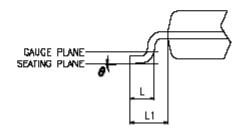


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PACKAGE OUTLINE DIMENSION

48-pin 12mm x 20mm TSOP-I Package Outline Dimension





VARIATIONS (ALL DIMENSIONS SHOWN IN MM)

	MANAGER ATT SUMPLISHED ALL ALL ALL ALL ALL ALL ALL ALL ALL AL					
	SYMBOLS	MIN.	NOM.	MAX		
	A	_	_	1.20		
	A1	0.05	_	0.15		
	A 2	0.95	1.00	1.05		
	Ь	0.17	0.22	0.27		
	c	0.10	_	0.21		
Δ		19.80	20.00	20.20		
Δ	□1	18.30	18.40	18.50		
Δ	E	11.90	12.00	12.10		
	B	(0.50 BAS	C		
	┙	0.50	0.60	0.70		
Δ	L1	_	0.80	_		
Δ	Υ	_	_	0.10		
Δ	θ	O.	_	5*		

NOTES:

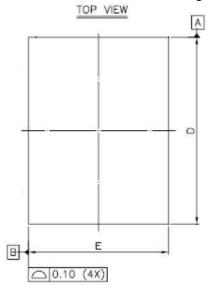
- 1 JEDEC OUTLINE : MO-142 DD
- 2.PROFILE TOLERANCE ZONES FOR 01 AND E DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION ON E IS 0.15 mm PER SIDE AND ON D1 IS 0.25 mm PER SIDE.
- 3.DIMENSION & DOES NOT INCLUDE DAMBAR PROTRUSION ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08mm TOTAL IN EXCESS OF THE & DIMENSION AT NAXIMUN MATERIAL CONDITION DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT.

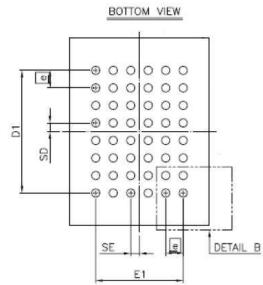


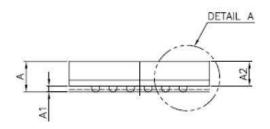
AS7C316098A

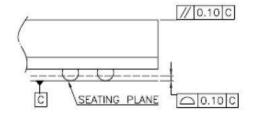
1024K X 16 BIT HIGH SPEED CMOS SRAM

48-ball 6mm × 8mm TFBGA Package Outline Dimension





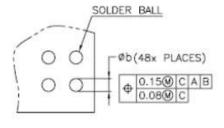




SIDE VIEW

DETAIL A

SYM.	DIMENSION (mm)			DIMENSION (inch)			
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	-	-	1.40	_	-	0.055	
A1	0.20	0.25	0.30	0.008	0.010	0.012	
A2	-	-	1.05	-	-	0.041	
b	0.30	0.35	0.40	0.012	0.014	0.016	
D	7.95	8.00	8.05	0.313	0.315	0.317	
D1	5.25 BSC			0.207 BSC			
E	5.95	6.00	6.05	0.234	0.236	0.238	
E1	3.75 BSC			0.148 BSC			
SE	0.375 TYP			0.015 TYP			
SD.	0.375 TYP			0.015 TYP			
e	0.75 BSC			0.030 BSC			



DETAIL B

NOTE:

CONTROLLING DIMENSION: MILLIMETER.
 REFERENCE DOCUMENT: JEDEC MO-207.



AS7C316098A 1024K X 16 BIT HIGH SPEED CMOS SRAM

ORDERING INFORMATION

Alliance	Organization	VCC Range	Package	Operating Temp	Speed ns
AS7C316098A-10TIN	1024K x 16	2.7 ~ 3.6V	48 pin TSOP-I	Industrial (-40 ~ 85°C)	10
AS7C316098A-10BIN	1024K x 16	2.7 ~ 3.6V	48 ball TFBGA 6mm x 8mm	Industrial (-40 ~ 85°C)	10



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